
Superconductivity in infinite-layer nickelates – The role of the capping layer

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The quest for a Ni-based analogous of cuprate high-T_c superconductors has reached a first success: Nd_{0.8}Sr_{0.2}NiO₂ thin films obtained after topotactic reduction of the perovskite Nd_{0.8}Sr_{0.2}NiO₃ have been found to host superconductivity below 15 K^[1]. From the preparation standpoint, an SrTiO₃ (STO) layer was firstly used as capping layer to obtain the superconducting state in Nd_{0.8}Sr_{0.2}NiO₂ films^[1], and beyond the assumption that it could allow for a better stabilization of the infinite-layer phase during topotactic reduction, its role is still unclear. Indeed, superconductivity was reported also for non-capped films, suggesting that it is not due to the presence of the capping layer^[2].

On the other hand, some properties of capped and un-capped samples are different, in particular the low energy excitation spectra. Indeed, while magnetic excitations (of about 200 meV energy loss) were observed for STO-capped samples of different Sr-content^[3], a charge ordering phenomenon was observed for the uncapped ones^[4]. The actual state-of-the-art imposes a thorough study of the role of the capping layer on the properties of the infinite-layer nickelates. Even the Stanford group, which started the field, did not yet perform a systematic study of the role of the capping. From an experimental perspective, this is certainly an issue that deserves further investigations.

The successful candidate will grow (R,Sr)NiO₃ (R=La,Nd,Pr) nickelate thin films by pulsed-laser-deposition and produce infinite-layer (R,Sr)NiO₂ thin films by topotactic reduction. Several capping layers will be used such as insulating (LaAlO₃)_{0.3}(Sr₂TaAlO₆)_{0.7} (LSAT) and/or STO, metallic Pt and/or Cu, and also polar like PbTiO₃. X-ray diffraction and atomic-force-microscopy techniques will be used to attest the quality of the as-grown and reduced thin films. Transport measurements will be performed with a Dynacool (Quantum Design) and synchrotron radiation will be used to obtain the requested information about the electronic structure of the differently capped infinite-layer thin films.

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